

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.036		V/°C	Reference to 25°C, $I_D = 1mA$
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.5	4.0	mΩ	V _{GS} = 10V, I _D = 95A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
gfs	Forward Trans conductance	106			S	$V_{DS} = 25V, I_{D} = 60A$
I _{DSS}	Drain-to-Source Leakage Current			20		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$
				250	μΑ	$V_{DS} = 32V, V_{GS} = 0V, T_{J} = 125$ °C
	Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage			200	- Λ	$V_{GS} = 20V$
I _{GSS}				-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 160	200		I _D = 95A
Q_{gs}	Gate-to-Source Charge	 35		nC	$V_{DS} = 32V$
Q_{gd}	Gate-to-Drain Charge	42	60		V _{GS} = 10V⊕⑦
$t_{d(on)}$	Turn-On Delay Time	17			$V_{DD} = 20V$
t _r	Rise Time	 140		no	$I_D = 95A$
$t_{d(off)}$	Turn-Off Delay Time	 72		ns	$R_G = 2.5\Omega$
t _f	Fall Time	26			R _D = 0.21Ω ④⑦
Ls	Internal Source Inductance	 7.5		n H	Between lead, and center of die contact
C_{iss}	Input Capacitance	7360			$V_{GS} = 0V$
C_{oss}	Output Capacitance	1680			$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	240		nE	f = 1.0MHz, See Fig. 5
C_{oss}	Output Capacitance	6630		рг	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
	Output Capacitance	 1490			$V_{GS} = 0V, V_{DS} = 32V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 1540			$V_{GS} = 0V$, $V_{DS} = 0V$ to 32V

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			162⑥		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			650		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 95A, V_{GS} = 0V $ ④
t _{rr}	Reverse Recovery Time		71	110	ns	$T_J = 25^{\circ}C, I_F = 95A$
Q_{rr}	Reverse Recovery Charge		180	270	nC	di/dt = 100A/µs ④⑦
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- \odot Starting T_J = 25°C, L = 0.12mH, R_G = 25 Ω , I_{AS} = 95A, V_{GS} =10V. (See fig. 12)
- $\label{eq:local_local_local} \ensuremath{\mathfrak{J}} \quad I_{SD} \leq 95A, \ di/dt \leq 150A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- \circ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ② Use IRF1404 data and test conditions.
- This is applied to D²Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- $^{\circ}$ R_θ is measured at T_J approximately 90°C.



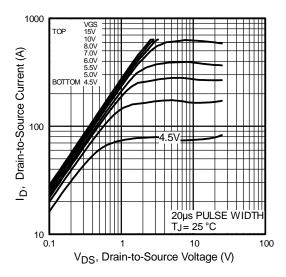


Fig. 1 Typical Output Characteristics

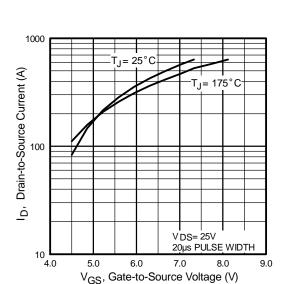


Fig. 3 Typical Transfer Characteristics

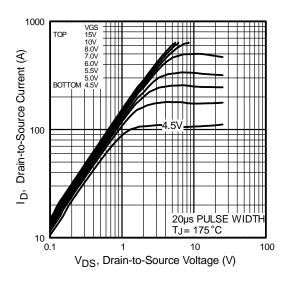


Fig. 2 Typical Output Characteristics

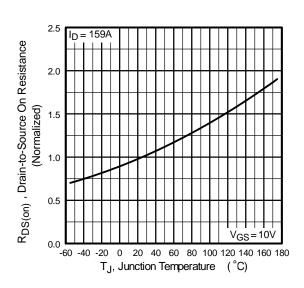


Fig. 4 Normalized On-Resistance Vs. Temperature

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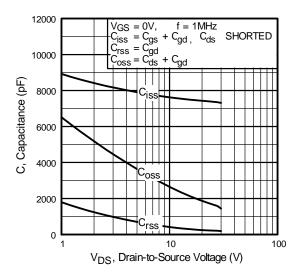


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

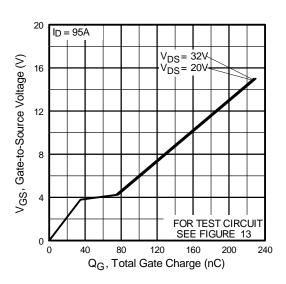


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

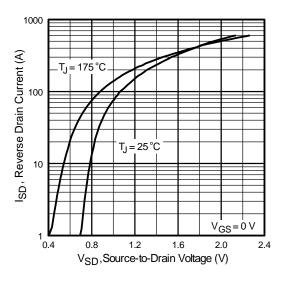


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

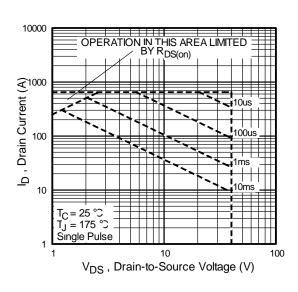


Fig 8. Maximum Safe Operating Area



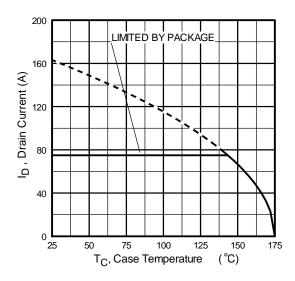


Fig 9. Maximum Drain Current vs. Case Temperature

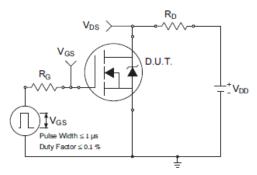


Fig 10a. Switching Time Test Circuit

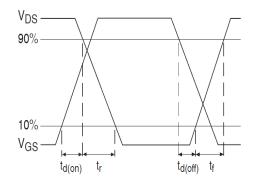


Fig 10b. Switching Time Waveforms

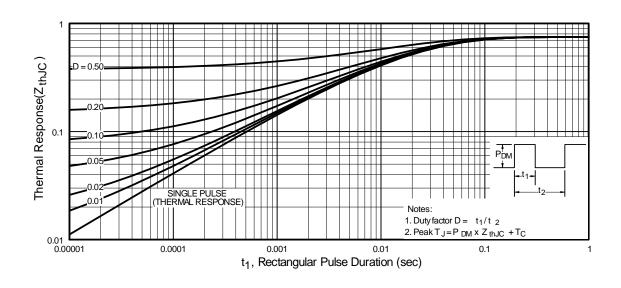


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



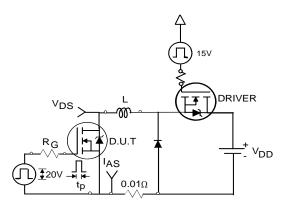


Fig 12a. Unclamped Inductive Test Circuit

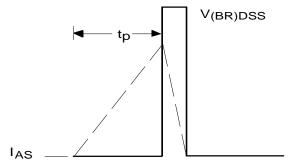


Fig 12b. Unclamped Inductive Waveforms

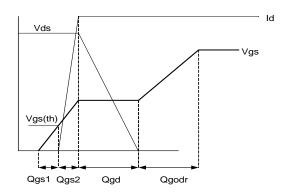


Fig 13a. Gate Charge Waveform

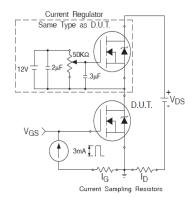


Fig 13b. Gate Charge Test Circuit

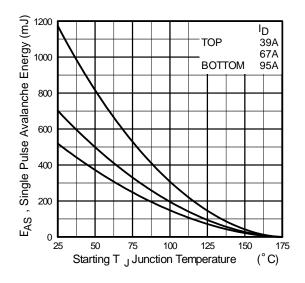


Fig 12c. Maximum Avalanche Energy vs. Drain Current

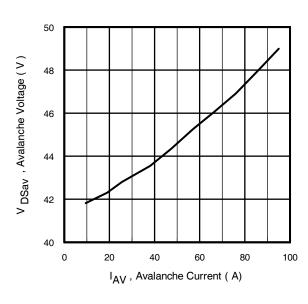
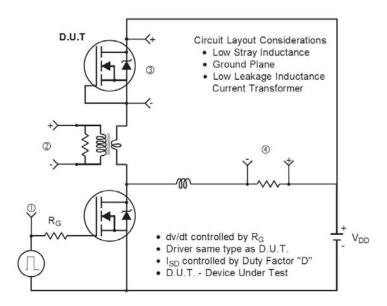


Fig 12d. Typical Drain-to-Source Voltage Vs. Avalanche Current



Peak Diode Recovery dv/dt Test Circuit



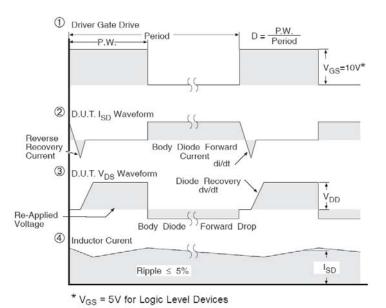
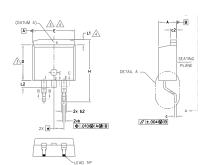
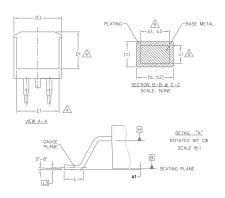


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S Y M	DIMENSIONS						
B	MILLIM	ETERS	INC	INCHES			
L	MIN.	MAX.	MIN.	MAX.	O T E S		
А	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
ь	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
b3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	_	.270	_	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	_	.245	_	4		
е	2.54	BSC	.100	BSC			
Н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	_	1.68	_	.066	4		
L2	_	1.78	_	.070			
L3	0.25	0.25 BSC .01					

LEAD ASSIGNMENTS

DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

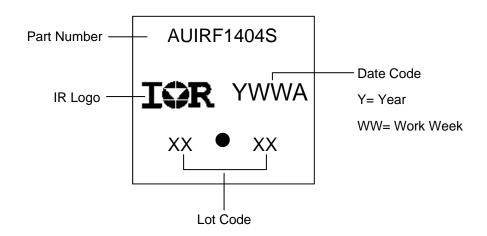
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

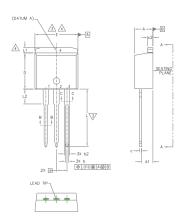
2, 4.- COLLECTOR 3.- EMITTER

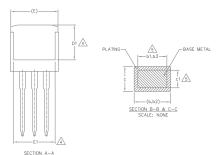
D²Pak (TO-263AB) Part Marking Information





TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.

6. CONTROLLING DIMENSION: INCH.

7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

HEXFET

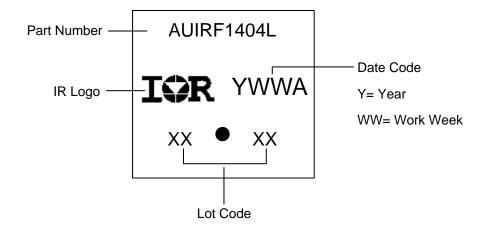
DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE 1.- GATE

2.- DRAIN 3.- SOURCE 4.- DRAIN

S Y M	DIMENSIONS						
В	MILLIM	ETERS	INC	INCHES			
0 L	MIN.	MAX.	MIN.	MAX.	O T E S		
Α	4.06	4.83	.160	.190			
A1	2.03	3.02	.080	.119			
b	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
ь3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	-	.270	_	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245		4		
е	2.54	BSC	.100	BSC			
L	13.46	14.10	.530	.555			
L1	_	1.65	_	.065	4		
L2	3.56	3.71	.140	.146			

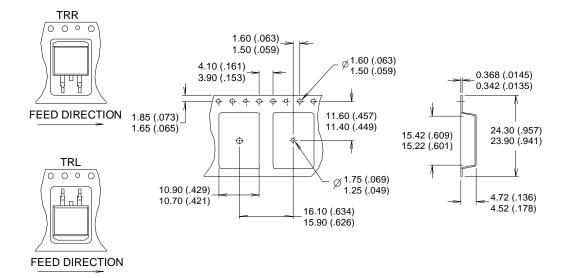
TO-262 Part Marking Information

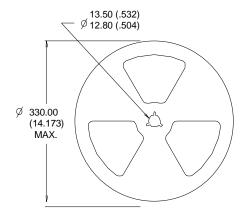


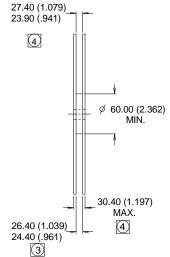
2015-11-11



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

10



Qualification Information

<u></u>	uon muonnauon					
		Automotive (per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
		TO-262	MCI 4			
Woisture	Moisture Sensitivity Level		MSL1			
	Maghina Madal		Class M4 (+/- 425V) [†]			
	Machine Model	AEC-Q101-002				
50 5	III area Bed Madel	Class H2 (+/- 4000V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Ohana I Daria Madal	Class C5 (+/-1125V) [†]				
	Charged Device Model	AEC-Q101-005				
RoHS Compliant		Yes				
		1				

† Highest passing voltage.

Revision History

Date	Comments			
11/11/2015	Updated datasheet with corporate template			
11/11/2015	Corrected ordering table on page 1.			

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